

Search Notes

Application/Control No.

10/816,178

Examiner

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Applicant(s)/Patent under
Reexamination

JOHNSON ET AL.

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
327	2,3,7,12	5/24/2005	HLN
	39-43,47		
	49,162		
	163		
331	25,DIG.2		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Shepardize Search	5/25/2005	HLN